

Robust Sensors for Structural Health Monitoring in Extreme Harsh Environments



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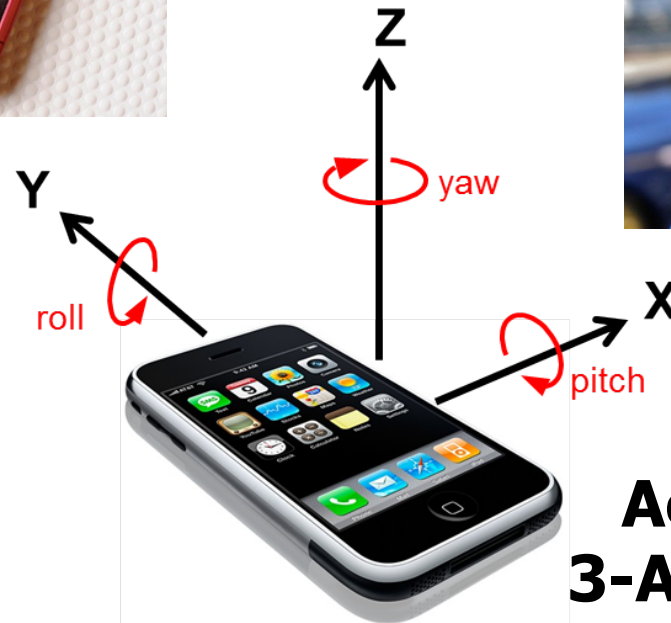
**International Workshop on Structural Health Monitoring
12 September 2013**

Sensors in iPhones

Digital Compass [1]



Proximity & Ambient Light Sensors [2]



Accelerometers & 3-Axis Gyroscope [3]

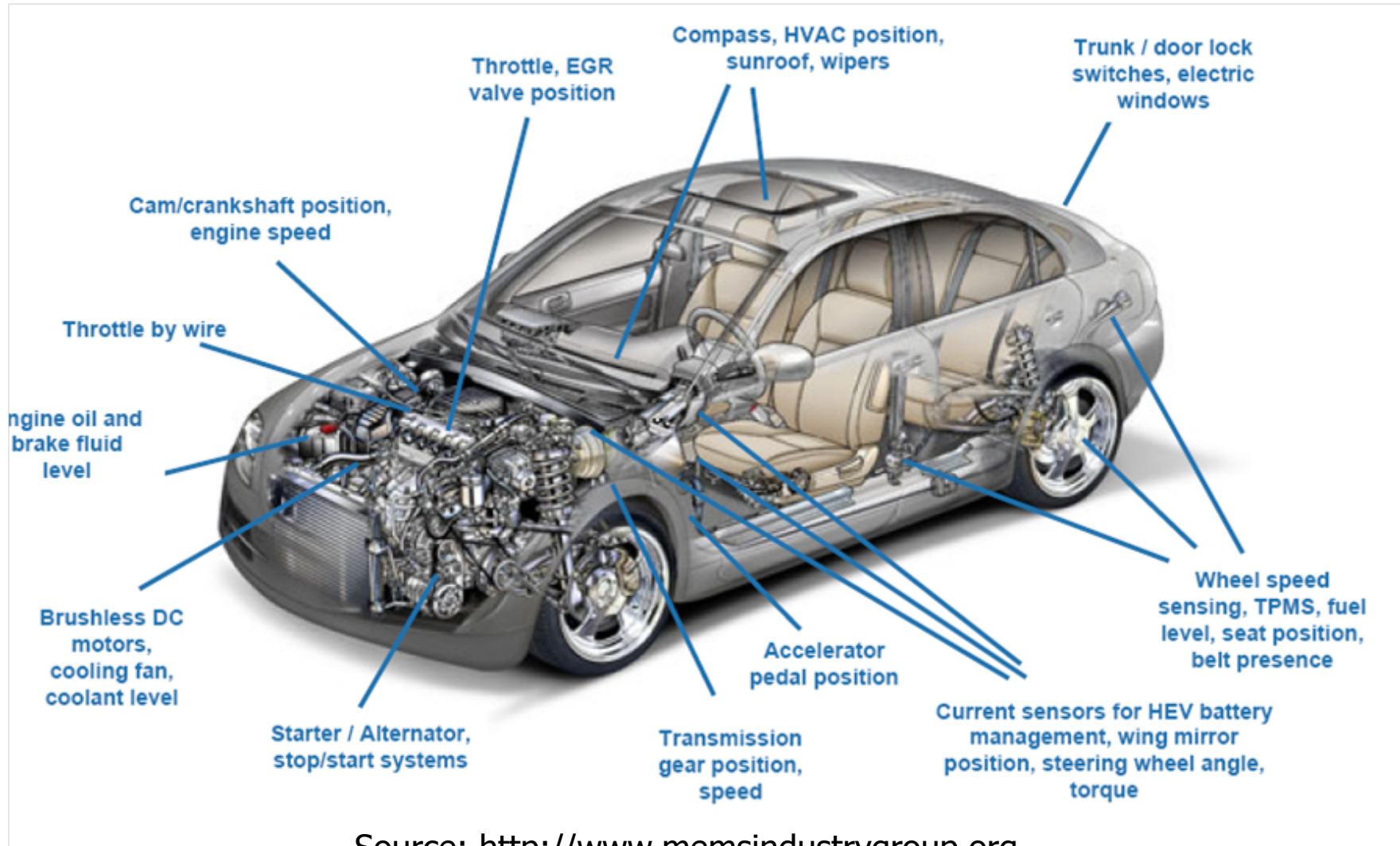
Image credits:

[1] www.upaa.org

[2] www.readwrite.com

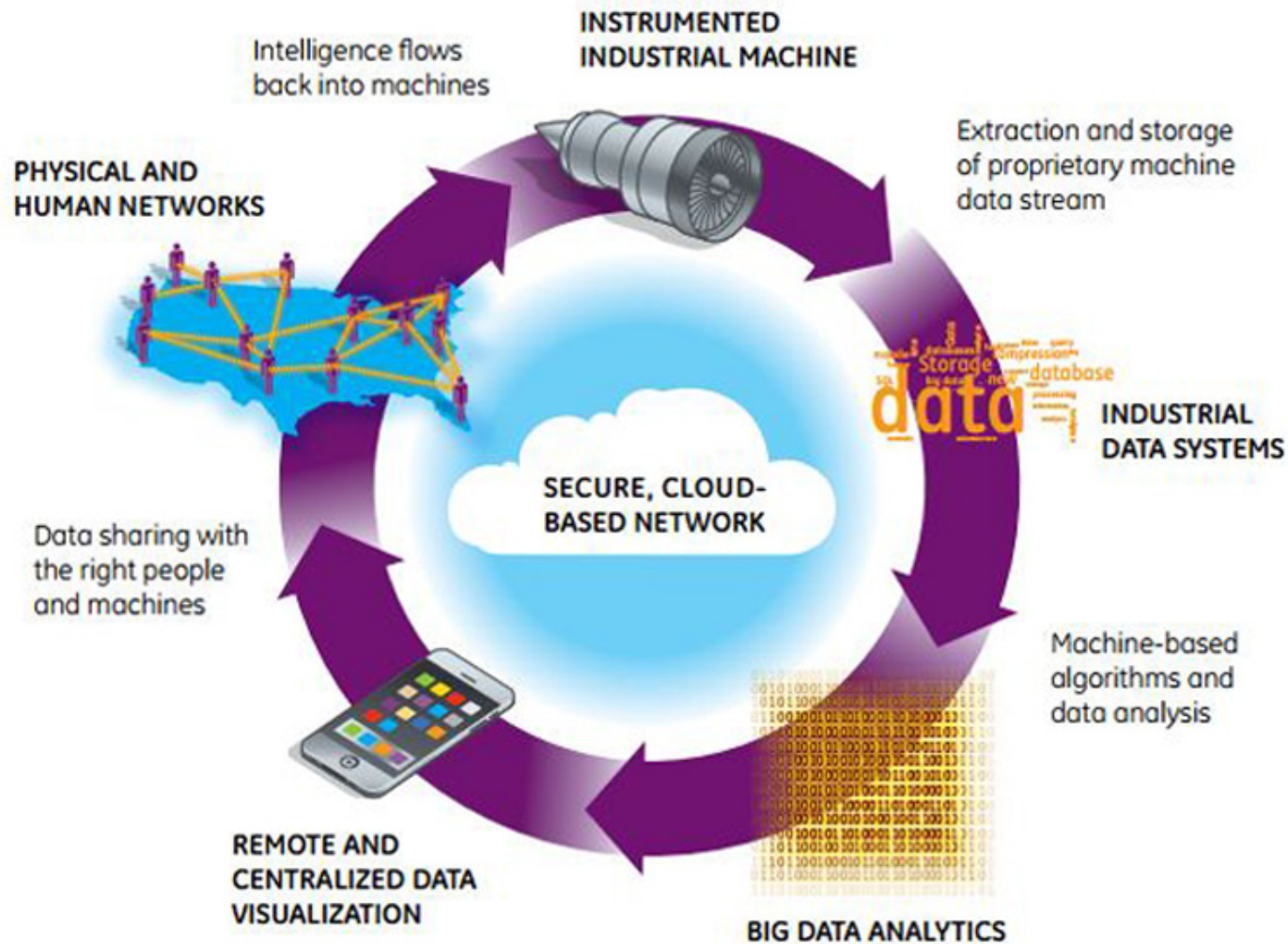
[3] www.hillcrestlabs.com

Sensors in Cars



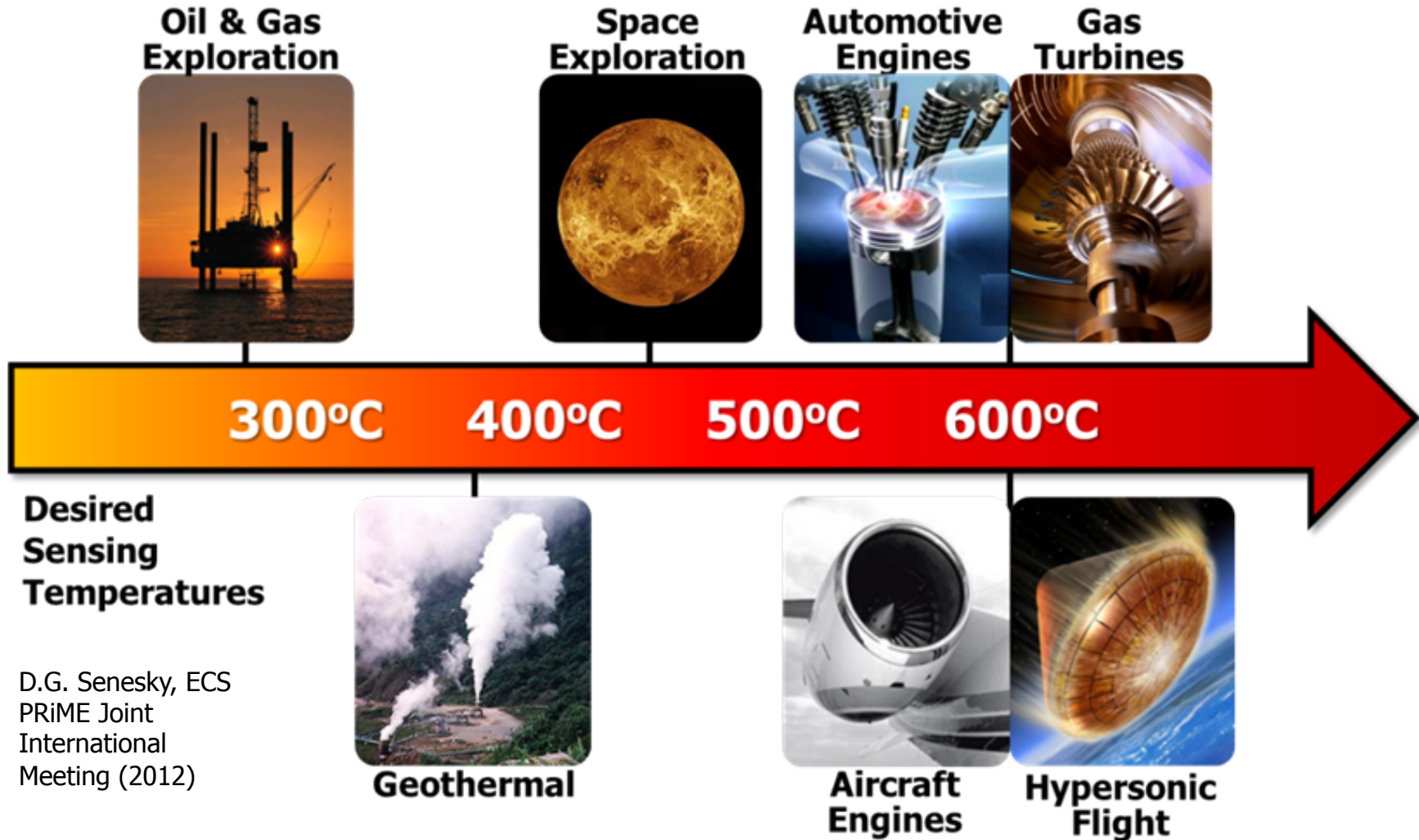
Source: <http://www.memsiindustrygroup.org>

The Industrial Internet of Things



Extreme Harsh Environment

- A “extreme harsh environment” includes extremes of temperature, pressure, shock, radiation and chemical attack.

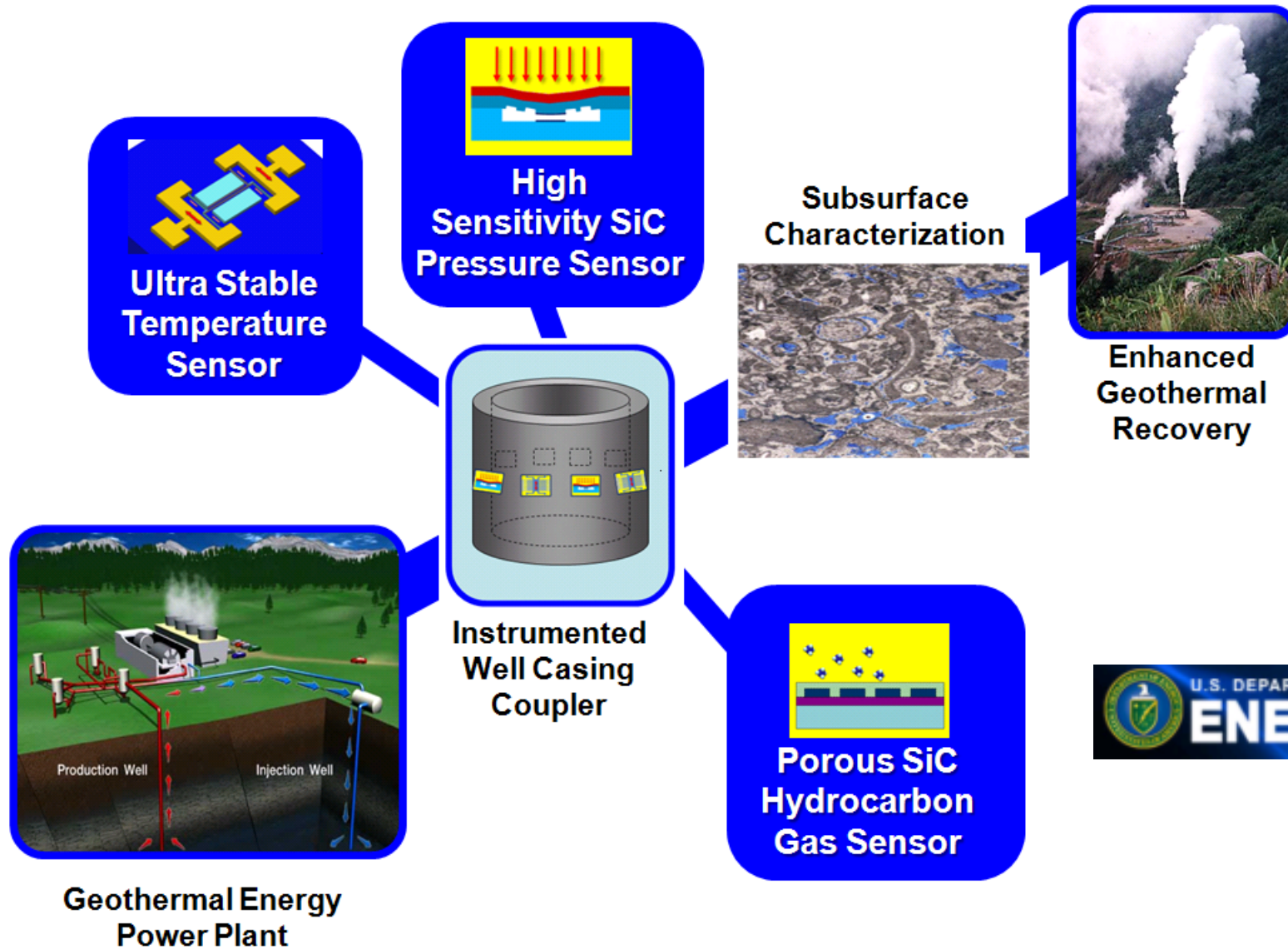


D.G. Senesky, ECS
PRiME Joint
International
Meeting (2012)

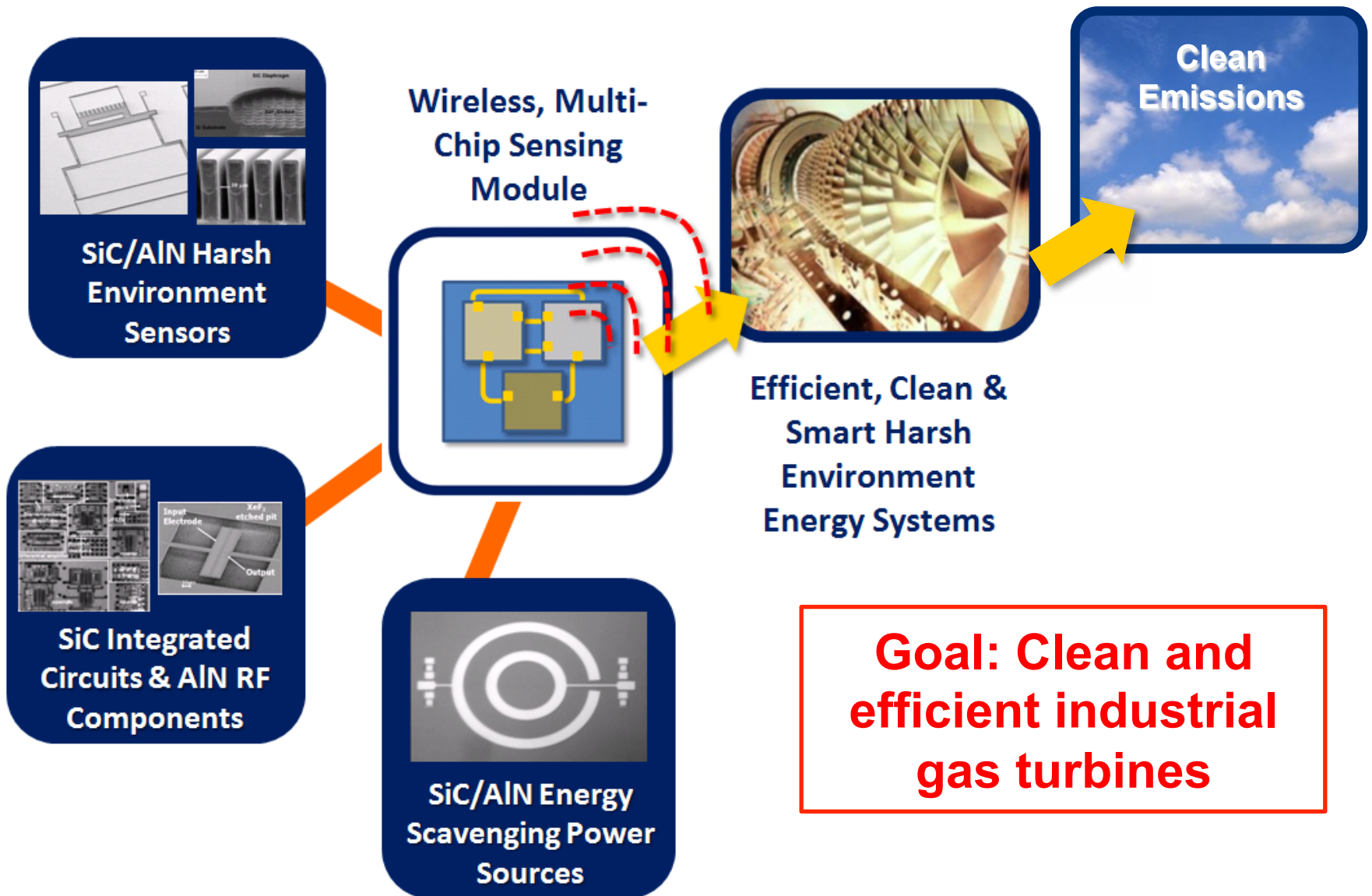
Real-time Sensing in Harsh Environments

- Sensing within harsh environments enables real-time monitoring of combustion processes, subsurface properties, critical components, and space environments.
 - ↳ Subsurface: *pressure, temperature, flow, tilt and chemical conc.*
 - ↳ Combustion: *pressure, temperature and flame speed*
 - ↳ Space: *pressure, radiation, strain and magnetic fields*
- Commercial-off-the-shelf sensors and electronics are limited to temperatures below 200°C and short operation periods.
- Technical challenges:
 - ↳ A new materials platform must be utilized to extend the operation limits (**up to 600°C**).
 - ↳ New sensing methodologies (e.g. packaging, temperature compensation, communication and power) must be developed.

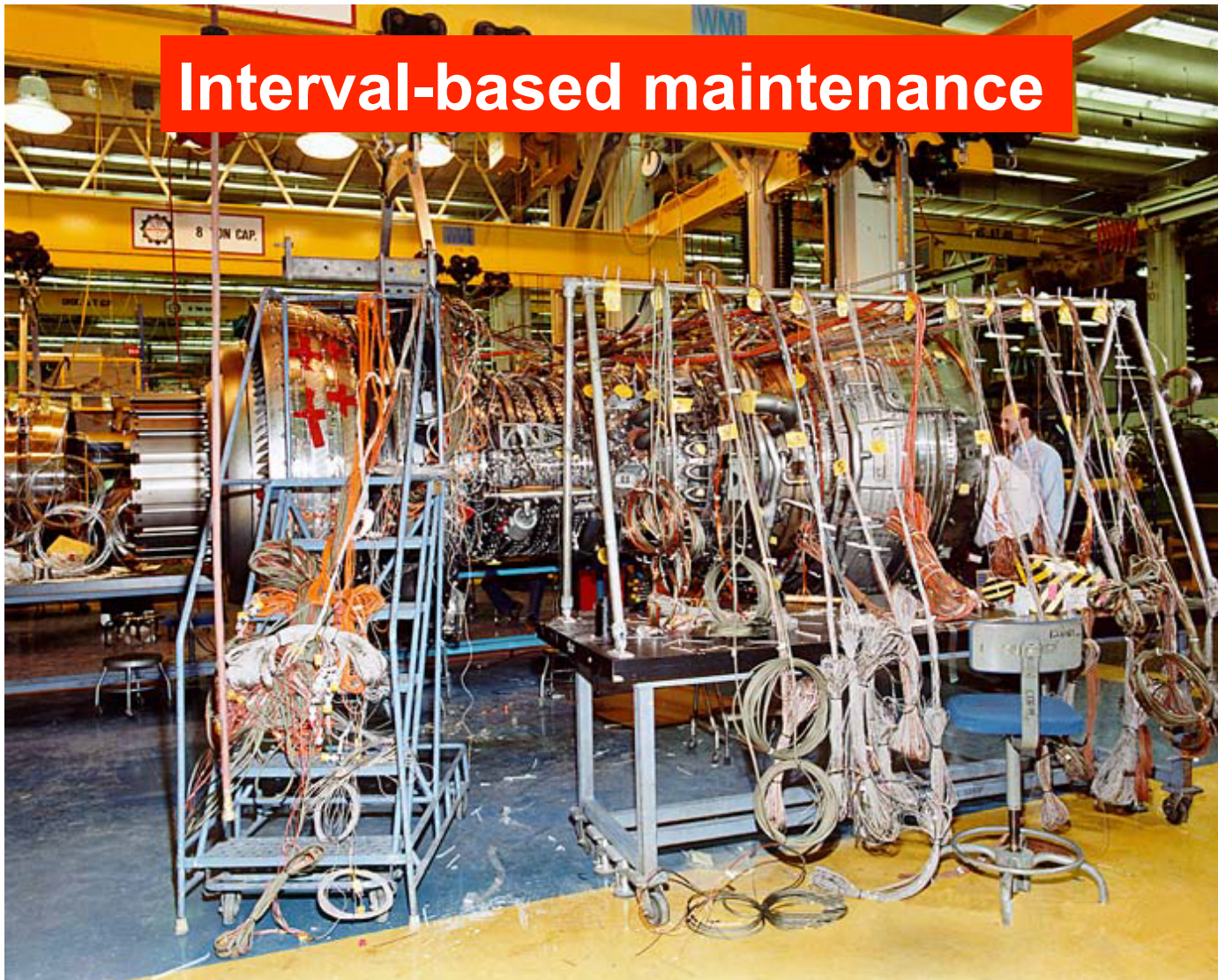
Subsurface Monitoring



In-situ Combustion Monitoring

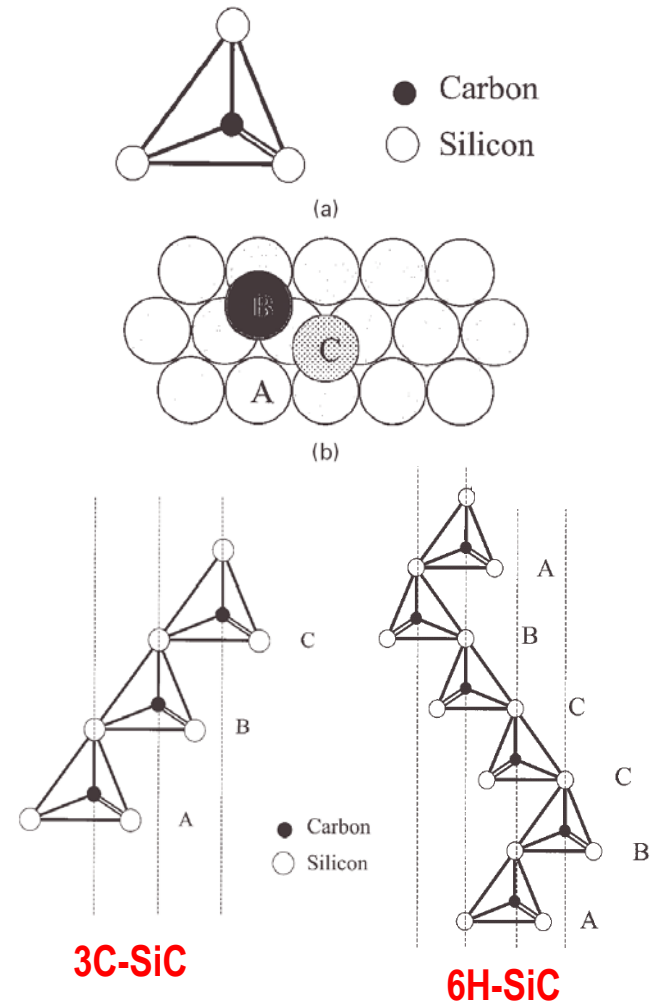


Current Technology



Silicon Carbide (SiC)

- **Semiconductor material**
 - ↳ p-type with Al doping
 - ↳ n-type with N doping
- **200+ polytypes have been identified**
 - ↳ Commonly used polytypes are 3C-SiC, 4H-SiC and 6H-SiC
 - ↳ 4H-SiC is the dominant polytype for the power electronics industry.



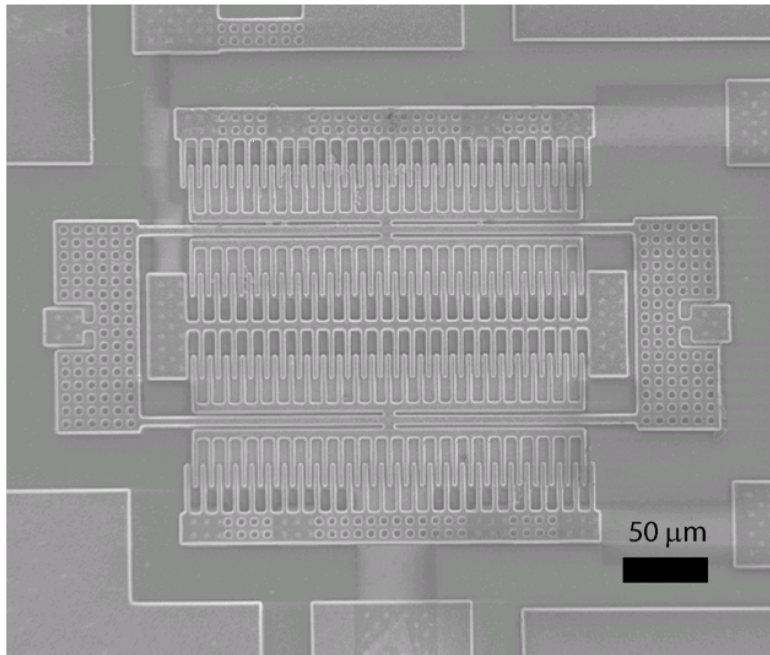
Schematic of atomic arrangement and stacking order of SiC (M. Mehregany et al.).

Material Properties (SiC)

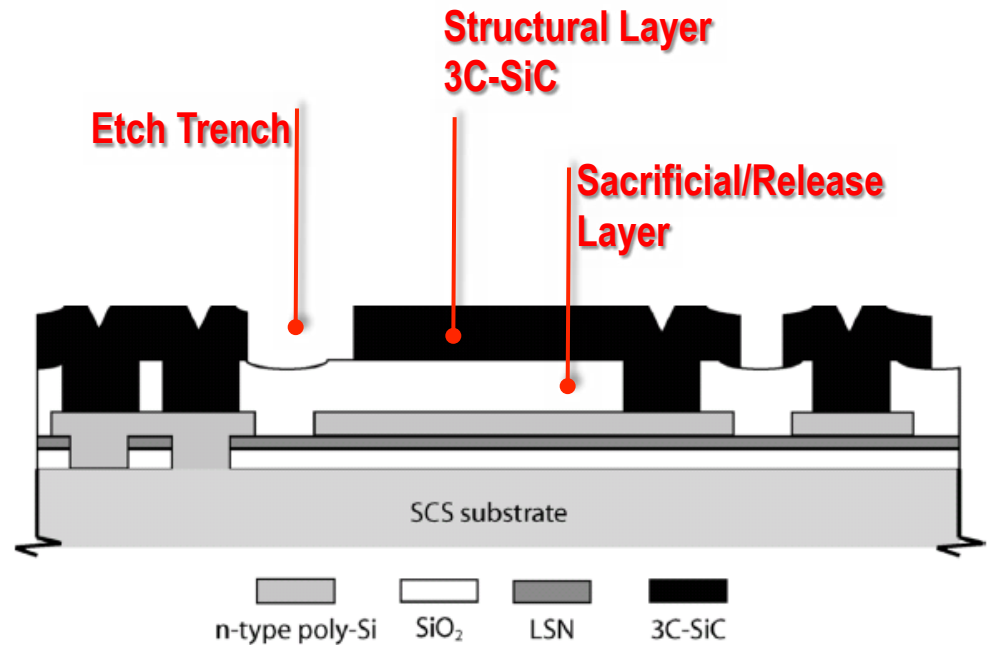
Property	6H-SiC	GaN	AlN	Diamond	Silicon
Melting Point (°C)	2830 sublimes	2500	2470	4000 phase change	1420
Energy Gap (eV)	3.0	3.4	6.2	5.6	1.12
Critical Field ($\times 10^6$ V/cm)	2.5	5.0	10	5.0	0.25
Thermal Conductivity (W/cm-K)	5.0	1.3	1.6	20	1.5
Young's Modulus (GPa)	450	390	340	1035	190
Acoustic Velocity ($\times 10^3$ m/s)	11.9	8.0	11.4	17.2	9.1
Yield Strength (GPa)	21	-	-	53	7
Coeff. of Thermal Expansion ($^{\circ}\text{C} \times 10^{-6}$)	4.5	3.7	4.0	0.8	2.6
Chemical Stability	Excellent	Good	Good	Fair	Fair

Material properties of SiC, AlN, GaN, diamond and Si.

SiC Resonant Strain Gauge



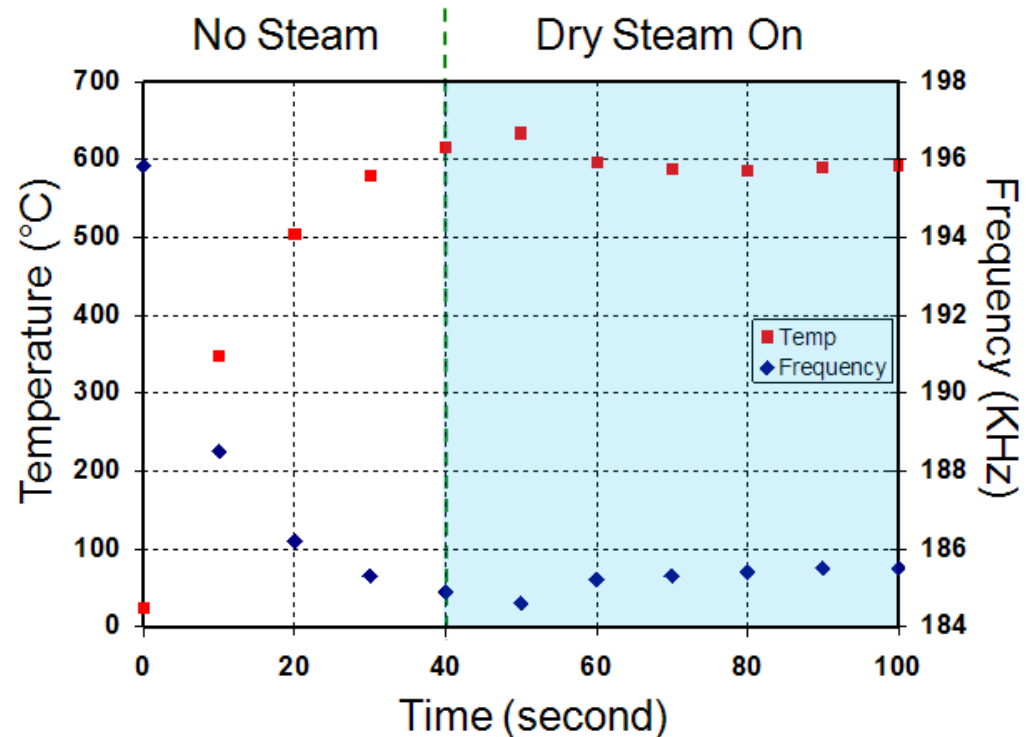
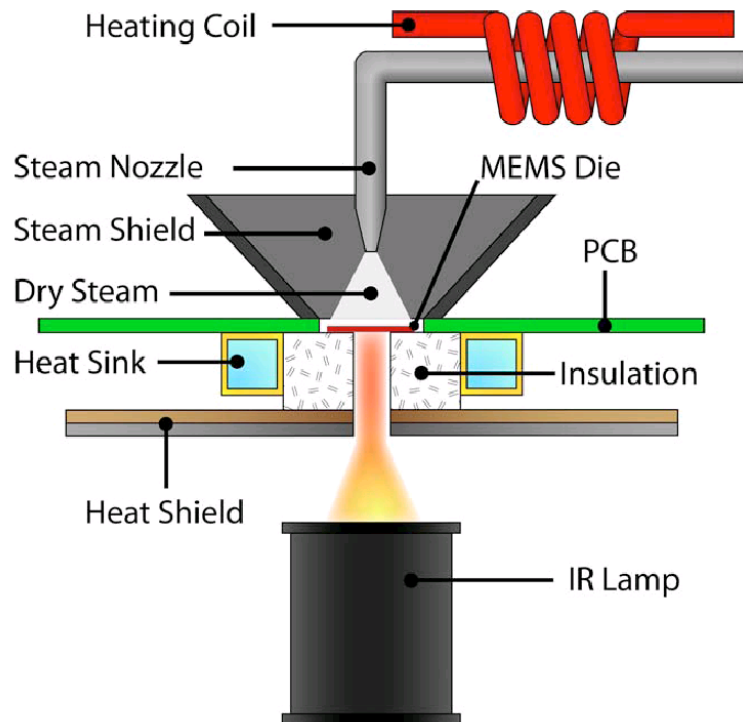
SEM image of polycrystalline 3C-SiC (7 μ m thick) resonant strain sensor.



Cross-sectional image of the SiC strain sensor fabrication process.

1. D.G. Senesky, B. Jamshidi, K.B. Cheng, and A.P. Pisano, IEEE Sensors Journal (2009)
2. R.G. Azevedo, D.G. Jones (Senesky), A. V. Jog, B. Jamshidi, D. R. Myers, L. Chen, X. Fu, M. Mehregany, M. B. J. Wijesundara, & A.P. Pisano, IEEE Sensors Journal (2007)

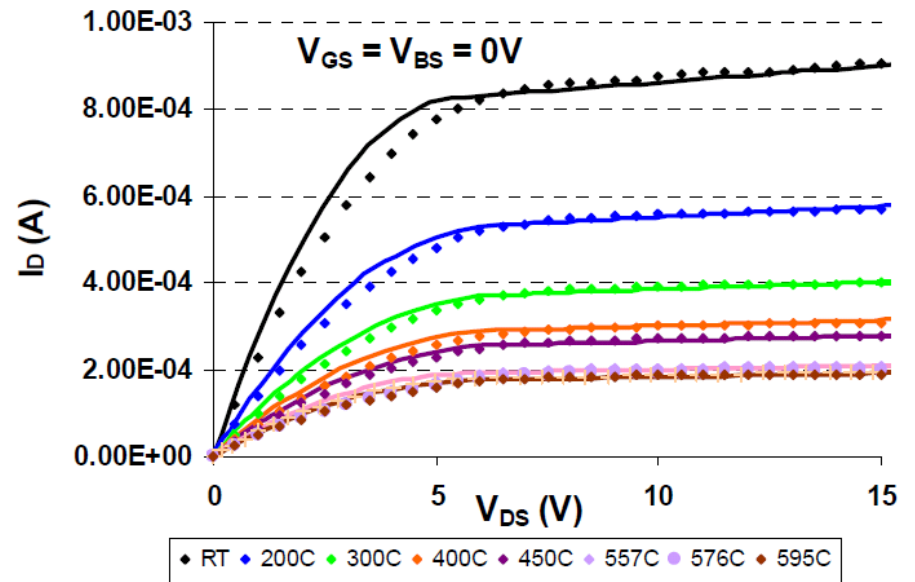
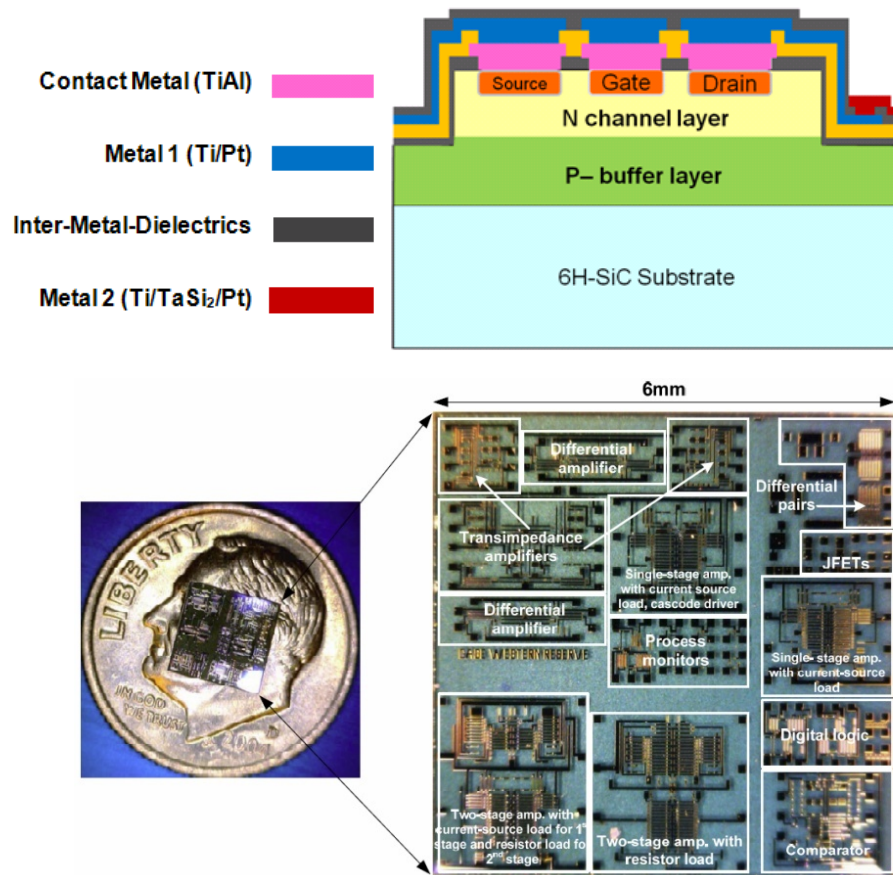
SiC Sensor Operation at 600°C



- The polycrystalline 3C-SiC sensor resonates in air and can operate at **600°C** in **dry steam**
- The strain sensor has a sensitivity of **66 Hz/ $\mu\epsilon$** and resolution of **0.045 $\mu\epsilon$** in a **10 kHz** bandwidth
- This poly-SiC sensor utilizes a fabrication process that can be utilized realize other harsh environment sensors.

D. R. Myers et al., J. Micro/Nanolith. MEMS MOEMS (2009)

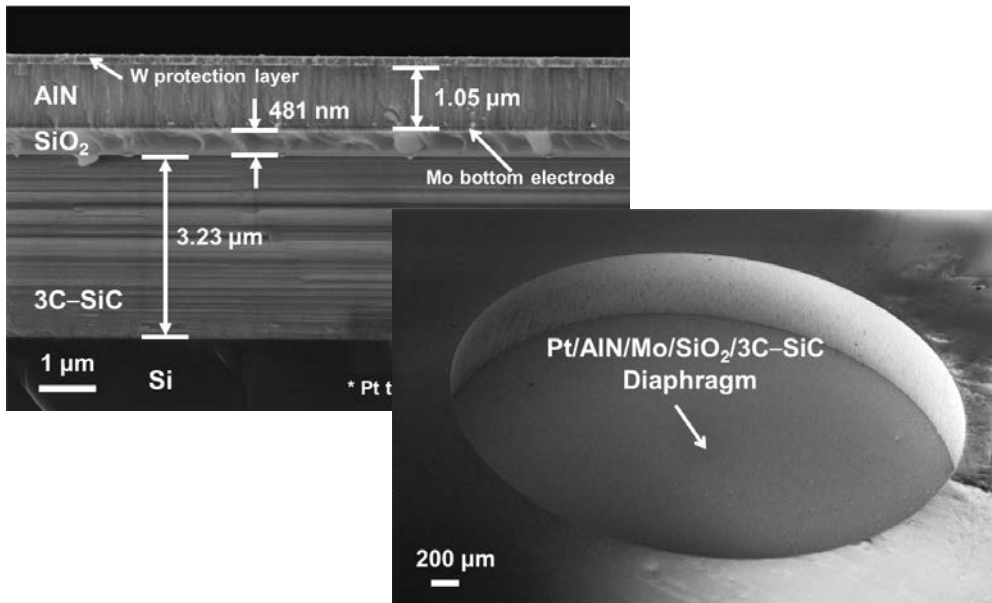
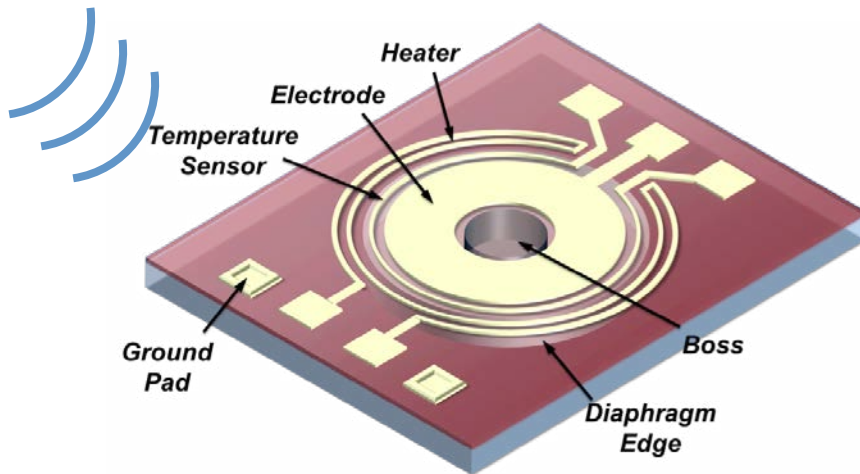
SiC JFET at 600°C



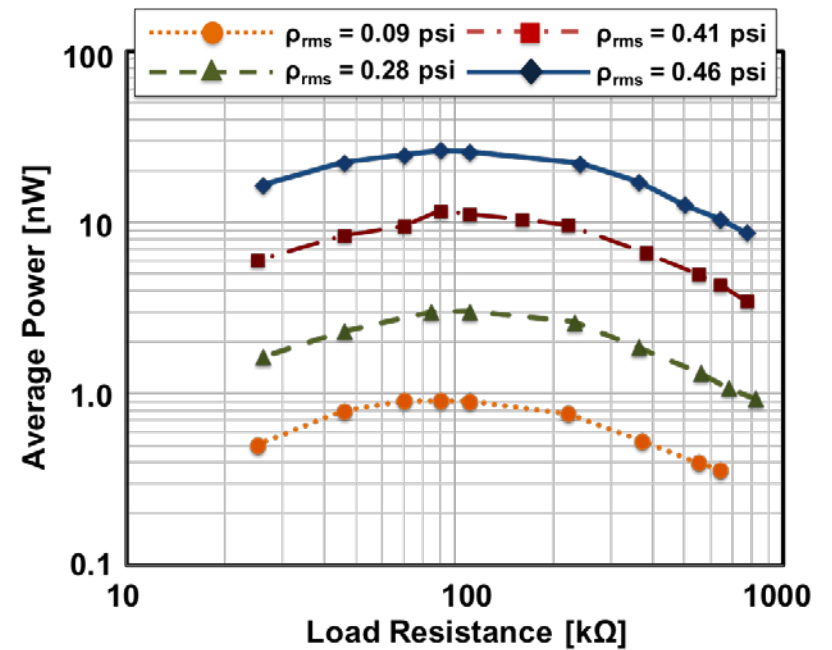
Measured I-V of JFET with $W/L = 100 \mu m / 10 \mu m$ for temperatures up to 600°C. Symbols mark measured values while solid curves show fit to the 3/2-power model.

A. Patil, M. Mehregany and S. Garverick, Ph.D. Thesis (2009)

SiC/AIN Energy Harvesting

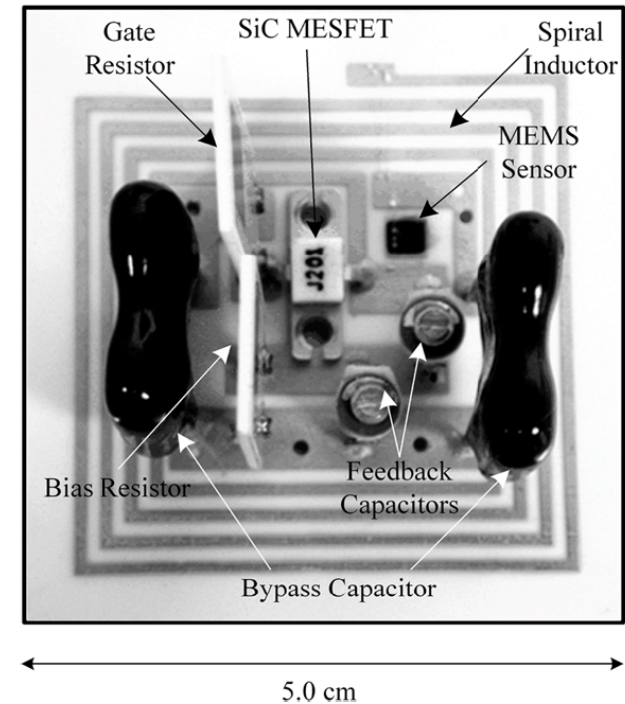
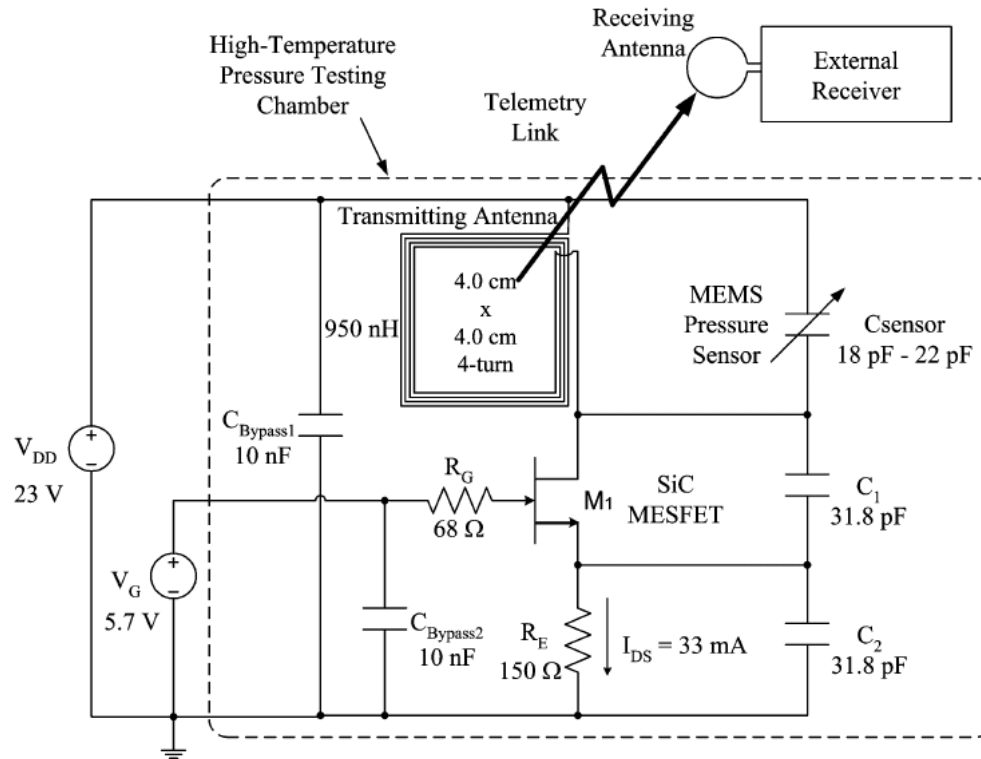


Output Power for Various Pressure Pulsations at 1 kHz



Y.J. Lai et al., Hilton Head Conference (2012).

High-Temperature Wireless



Telemetry module (Colpitts circuit) utilizing a SiC MESFET operated up to 400°C with a telemetry distance of approximately 1.0 m.

R. Wang, W. H. Ko, and D. J. Young, IEEE Sensors Journal (2005)

Material Properties (Gallium Nitride)

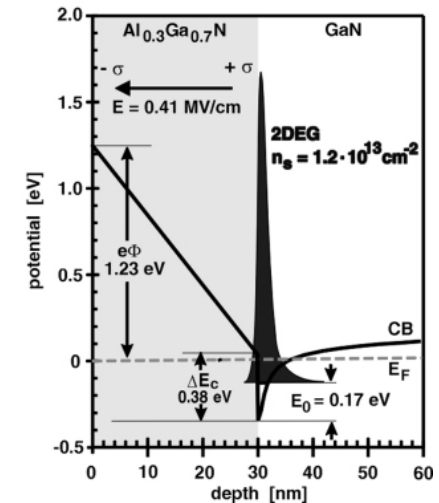
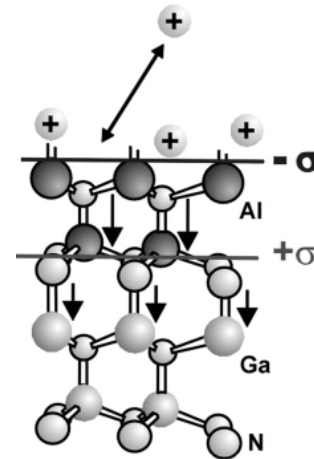
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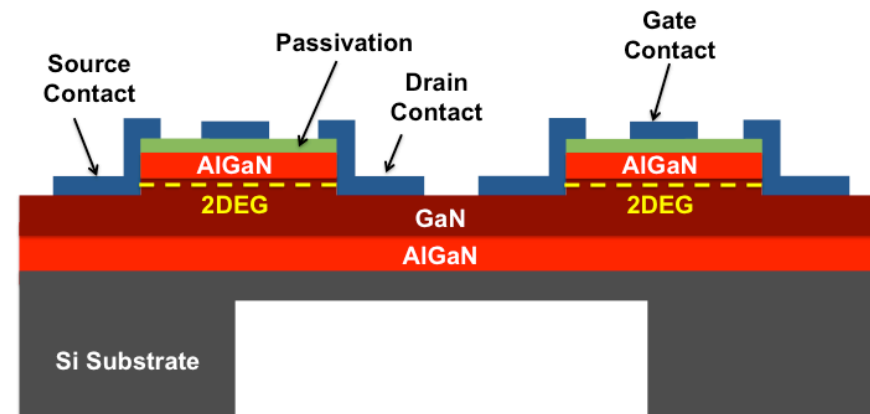
AlGaN/GaN Sensor Development

- The AlGaN/GaN heterostructure is currently being developed to make high electron mobility transistors (HEMTs) for the power electronics industry.
- The piezoelectric, polarization-induced, 2-dimensional electron gas (2DEG) at the AlGaN/GaN interface can improve the sensitivity of sensing devices.

- ↳ Spontaneous polarization-induced charges (at surface and interface)
- ↳ Strain sensitive
- ↳ Ion sensitive



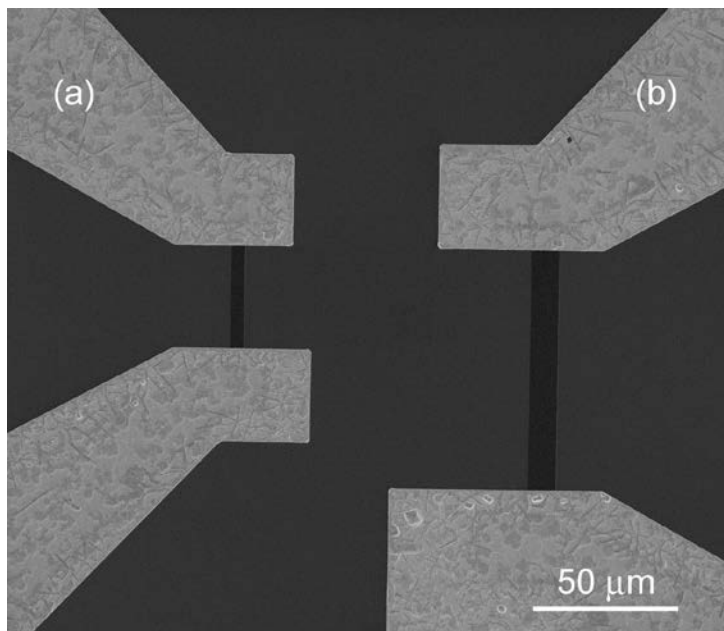
The jump in the macroscopic polarization (discontinuity in dipoles) at the AlGaN/GaN interface causes a positive fixed polarization charge at this interface [M. Stutzmann, et al.].



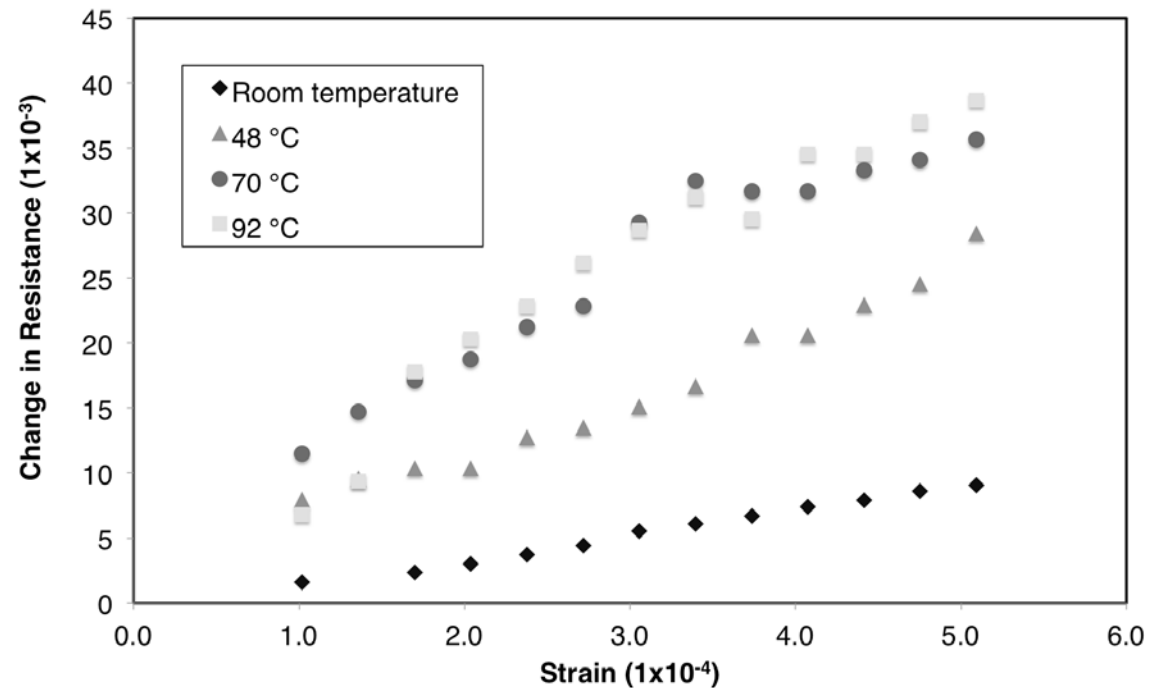
Cross-sectional image of fabrication process for AlGaN/GaN high electron mobility (HEMT) based sensors.

AlGaN/GaN Strain Gauges

Gauge Factor = -81 at 92°C



SEM image of AlGaN/GaN high electron mobility (HEMT) based strain sensors.



Experimental data obtained from characterization of AlGaN/GaN strain sensors at elevated temperatures.

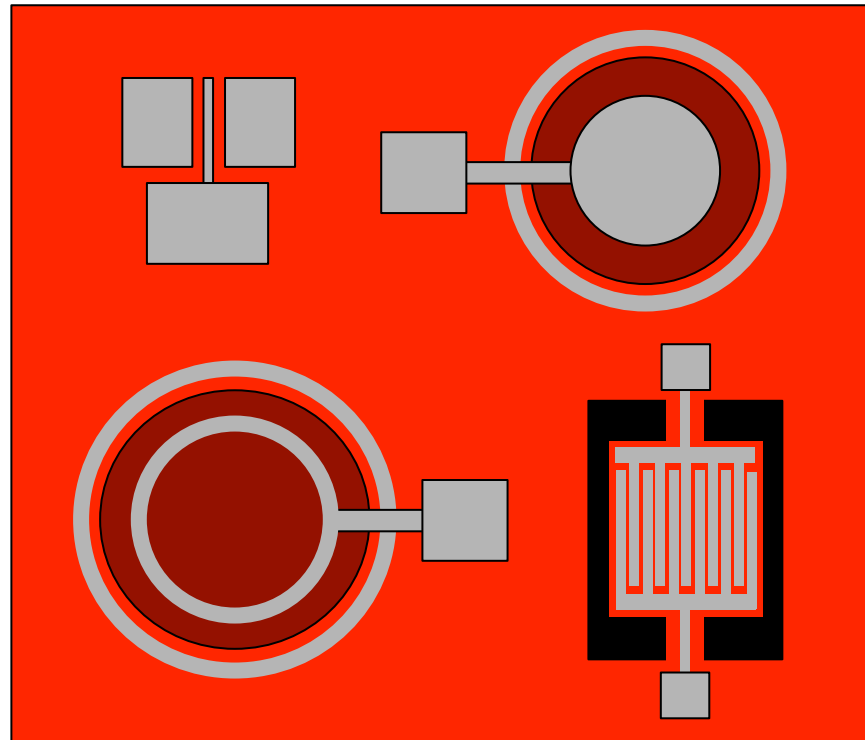
C.A. Chapin, H. Chiamori, M. Hou & D.G. Senesky, International Workshop on Structural Health Monitoring (2013)

AlGaN/GaN Device Integration

- Development of multiple devices (HEMT circuits, energy harvesters, sensors and RF resonators) on a single chip using the multi-functional properties of the AlGaN/GaN heterostructure.

**GaN High
Electron
Mobility
Transistor
(HEMT) Circuit**

**GaN
Piezoelectric
Energy
Harvester**

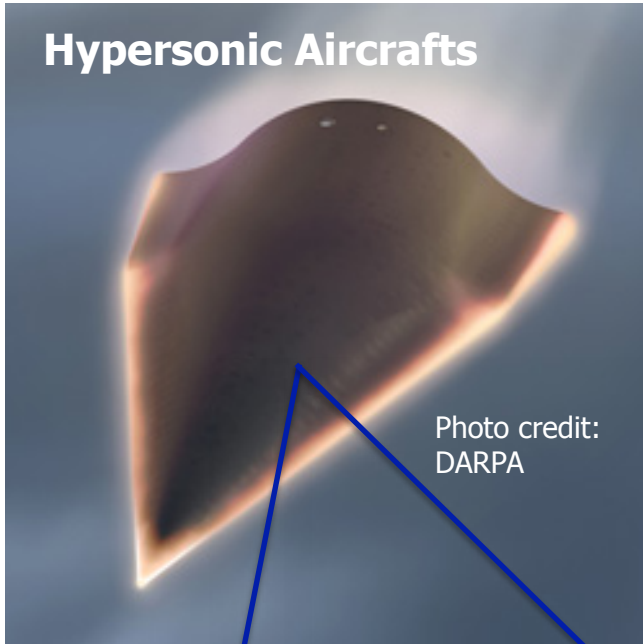


**GaN Sensors
(e.g. acoustic,
acceleration,
pressure)**

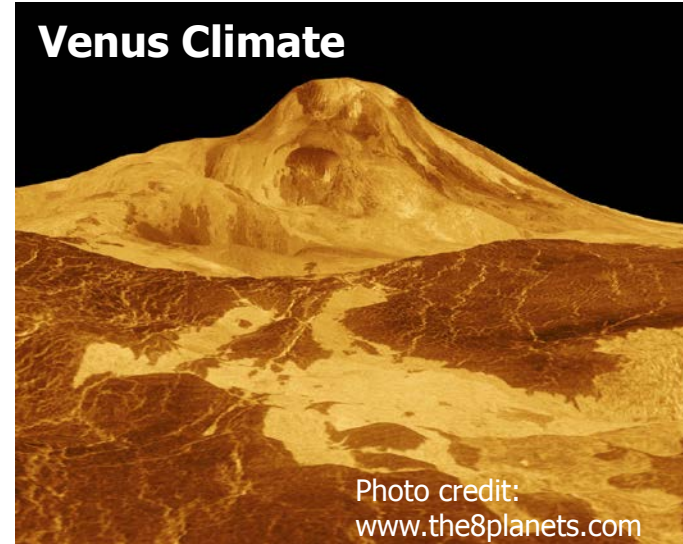
**GaN
Piezoelectric
RF Resonators**

Monitoring of Hot Structures & Hot Climates

Hypersonic Aircrafts



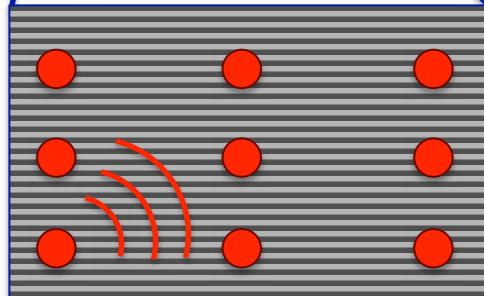
Venus Climate



Hydrothermal Vents



**"Smart" Hot
Structure with
Embedded
Sensors**



NASA's MEDLI Suite

Mars Science Laboratory Entry, Descent, and Landing Instrument (MEDLI) Suite

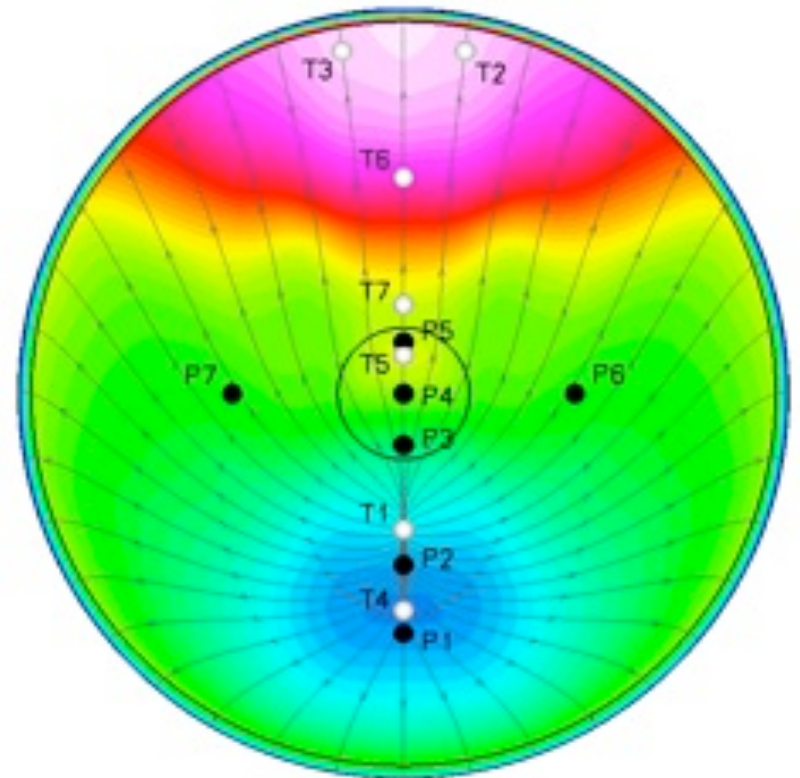
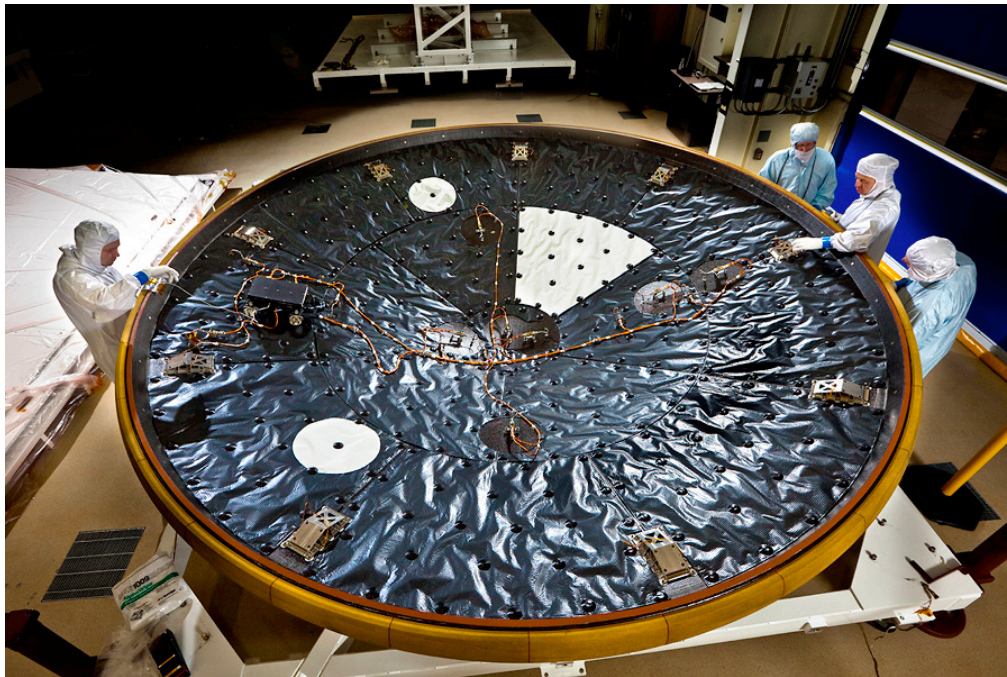


Image Credit: NASA JPL MEDLI Program

Conclusions

- **Ceramic semiconductor materials (SiC, AlN & GaN) can extend the operation environments of sensors and electronics.**
- **Harsh environment sensors can be used to**
 - ↳ Illuminate properties (e.g. pressure, temperature, and gas content) of combustion processes & subsurface conditions.
 - ↳ Monitor the structural health of critical components.
 - ↳ Provide real-time feedback.
- **In addition, these materials can be used to create a multitude of devices (sense, power, processing and communication) on a single chip.**

SPECIAL SESSION: SHM for Harsh Environments

- UC Berkeley, “Aluminum Nitride High Temperature Strain Sensors”
- UC Berkeley, “MEMS Piezoelectric Energy Harvesters for Harsh Environment Sensing”
- GE Global Research, “Optical MEMS Pressure Sensors for Geothermal Well Monitoring”
- Stanford University, “Development of High Performance BS-PT Based Piezoelectric Transducer for Structural Health Monitoring of High-Temperature Polymer-Matrix Composite Structures”
- NASA Ames, “Development and Verification of an Aerothermal Thermal Protection System Heat Shield Instrumentation Plug for Flight on Mars Science Laboratory”
- Stanford University, “Characterization of Gallium Nitride Heterostructures for Strain Sensing at Elevated Temperatures”

1:30 pm

HC 200-002

Acknowledgements

UC Berkeley:

- Prof. Albert P. Pisano
- Prof. Roya Maboudian
- BMAD Laboratory
- BSAC

Case Western Reserve University:

- Prof. Mehran Mehregany
- Prof. Steve Garverick

Stanford University:

- Dr. Heather Chiamori
- Ms. Caitlin Chapin
- Ms. Minmin Hou
- Mr. Gautam Narasimhan
- Mr. Ashwin Shankar
- Mr. Ateeq Suria

Funding Sources:

DARPA

NASA

Thank You!

